

Notice of References Cited	Application/Control No. 10/540,033		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Shean C. Wu		Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	English translation for JP 2001-40354 by computer. http://www4.ipdl.inpit.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&N0120=01&N2001=2&N3001=2001-040354
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